Structural fault collapsing by superposition of BDDs for test generation in digital circuits
Ubar, Raimund-Johannes; **Mironov, Dmitri**; **Raik, Jaan**; **Jutman, Artur** Proceedings of the Eleventh International Symposium on Quality Electronic Design ISQED 2010 : March 22-24, 2010 San Jose, California USA 2010 / p. 250-257 : ill
https://ieeexplore.ieee.org/document/5450451